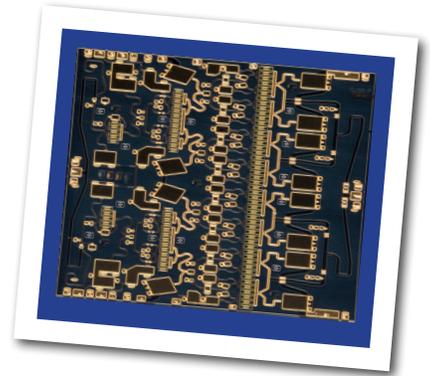


CMPA601C025D

25 W, 6.0 - 12.0 GHz, GaN MMIC, Power Amplifier

Cree's CMPA601C025D is a gallium nitride (GaN) High Electron Mobility Transistor (HEMT) based monolithic microwave integrated circuit (MMIC) on a silicon carbide substrate, using a 0.25 μm gate length fabrication process. GaN-on-SiC has superior properties compared to silicon, gallium arsenide or GaN-on-Si, including higher breakdown voltage, higher saturated electron drift velocity and higher thermal conductivity. GaN HEMTs also offer greater power density and wider bandwidths compared to Si, GaAs, and GaN-on-Si transistors. This MMIC contains a reactively matched amplifier design approach enabling very wide bandwidths to be achieved.



Typical Performance Over 6.0-12.0 GHz ($T_c = 25^\circ\text{C}$)

| Parameter | 6.0 GHz | 8.0 GHz | 10.0 GHz | 12.0 GHz | Units |
|---|---------|---------|----------|----------|-------|
| Small Signal Gain | 40.0 | 42.0 | 43.0 | 36.0 | dB |
| $P_{\text{OUT}} @ P_{\text{IN}} = 19 \text{ dBm}$ | 48.0 | 49.0 | 47.4 | 47.3 | dBm |
| $P_{\text{OUT}} @ P_{\text{IN}} = 19 \text{ dBm}$ | 63.0 | 79.0 | 55.0 | 54.0 | W |
| Power Gain @ $P_{\text{IN}} = 19 \text{ dBm}$ | 29.0 | 30.0 | 28.4 | 27.3 | dB |
| PAE @ $P_{\text{IN}} = 19 \text{ dBm}$ | 33.0 | 49.0 | 35.0 | 32.0 | % |

Note: All data pulse tested on-wafer with Pulse Width = 10 μs , Duty Cycle = 0.1%.

Features

- 32 dB Small Signal Gain
- 30 W Typical P_{SAT}
- Operation up to 28 V
- High Breakdown Voltage
- High Temperature Operation
- Size 0.172 x 0.239 x 0.004 inches

Applications

- Jamming Amplifiers
- Test Equipment Amplifiers
- Broadband Amplifiers
- Radar Amplifiers

Absolute Maximum Ratings (not simultaneous) at 25°C

| Parameter | Symbol | Rating | Units | Conditions |
|--|-----------------|-----------|----------|---|
| Drain-source Voltage | V_{DS} | 84 | V_{DC} | 25°C |
| Gate-source Voltage | V_{GS} | -10, +2 | V_{DC} | 25°C |
| Storage Temperature | T_{STG} | -55, +150 | °C | |
| Operating Junction Temperature | T_J | 225 | °C | |
| Maximum Forward Gate Current | I_{GMAX} | 15 | mA | 25°C |
| Maximum Drain Current ¹ | I_{DMAX} | 0.6 | A | Stage 1, 25°C |
| Maximum Drain Current ¹ | I_{DMAX} | 1.7 | A | Stage 2, 25°C |
| Maximum Drain Current ¹ | I_{DMAX} | 4.8 | A | Stage 3, 25°C |
| Thermal Resistance, Junction to Case (packaged) | $R_{\theta JC}$ | 0.83 | °C/W | 85°C, $P_{DISS} = 92.8$ W in 440213 package |
| Thermal Resistance, Junction to Case (die only) ² | $R_{\theta JC}$ | 0.36 | °C/W | 85°C, $P_{DISS} = 92.8$ W |
| Mounting Temperature (30 seconds) | T_S | 320 | °C | 30 seconds |

Note¹ Current limit for long term, reliable operation

Note² Eutectic die attach using 80/20 AuSn mounted to a 10mil thick CuMo carrier.

Electrical Characteristics (Frequency = 6.0 GHz to 12.0 GHz unless otherwise stated; $T_C = 25^\circ\text{C}$)

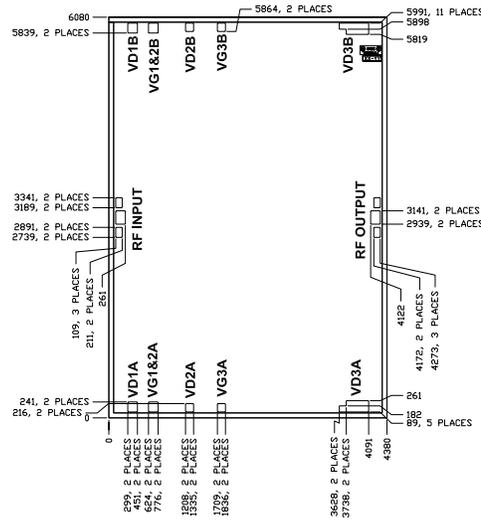
| Characteristics | Symbol | Min. | Typ. | Max. | Units | Conditions |
|---------------------------------------|-----------|------|-------|------|--------|---|
| DC Characteristics | | | | | | |
| Gate Threshold | V_{TH} | -3.8 | -2.8 | -2.3 | V | $V_{DS} = 10$ V, $I_D = 23.2$ mA |
| Drain-Source Breakdown Voltage | V_{BD} | 84 | 100 | - | V | $V_{GS} = -8$ V, $I_D = 23.2$ mA |
| RF Characteristics² | | | | | | |
| Small Signal Gain @ 6 GHz | S21 | 29.8 | 35 | - | dB | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 10$ dBm |
| Small Signal Gain @ 10 GHz | S21 | 30.2 | 35 | - | dB | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 10$ dBm |
| Small Signal Gain @ 12 GHz | S21 | 27.8 | 35 | - | dB | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 10$ dBm |
| Power Output | P_{OUT} | 45.5 | 47 | - | W | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm, Frequency = 6.0, 10.0, 12.0 GHz |
| Power Added Efficiency @ 6 GHz | PAE | 23.0 | 30 | - | % | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm |
| Power Added Efficiency @ 10 GHz | PAE | 23.3 | 32 | - | % | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm |
| Power Added Efficiency @ 12 GHz | PAE | 23.7 | 31 | - | % | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm |
| Power Gain | G_p | - | 28 | - | dB | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm |
| Input Return Loss | S11 | - | -10 | - | dB | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A |
| Output Return Loss | S22 | - | -8 | - | dB | $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A |
| Output Mismatch Stress | VSWR | - | 5 : 1 | - | Ψ | No damage at all phase angles, $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{OUT} = 25$ W CW |

Notes:

¹ Scaled from PCM data.

² All data pulse tested on-wafer with Pulse Width = 10 μ s, Duty Cycle = 0.1%.

Die Dimensions (units in microns)



Overall die size 4380 x 6080 (+0/-50) microns, die thickness 100 (+/-10) microns.
All Gate and Drain pads must be wire bonded for electrical connection.

| Pad Number | Function | Description | Pad Size (in) | Note |
|------------|----------|---|---------------|------|
| 1 | RF IN | RF-Input pad. Matched to 50 ohm. The DC impedance ~ 0 ohm due matching circuit. | 150 x 200 | 4 |
| 2 | VD1_A | Drain supply for stage 1A. VD = 28 V. | 150 x 150 | 1 |
| 3 | VD1_B | Drain supply for stage 1B. VD = 28 V. | 150 x 150 | 1 |
| 4 | VG1&2_A | Gate control for stage 1&2A. VG = -2.0 to - 3.5 V. | 150 x 150 | 1,2 |
| 5 | VG1&2_B | Gate control for stage 1&2B. VG = -2.0 to - 3.5 V. | 150 x 150 | 1,2 |
| 6 | VD2_A | Drain supply for stage 2A. VD = 28 V. | 129 x 129 | 1 |
| 7 | VD2_B | Drain supply for stage 2B. VD = 28 V. | 129 x 129 | 1 |
| 8 | VG3_A | Gate control for stage 3A. VG = -2.0 to - 3.5 V. | 129 x 129 | 1,3 |
| 9 | VG3_B | Gate control for stage 3B. VG = -2.0 to - 3.5 V. | 129 x 129 | 1,3 |
| 10 | VD3_A | Drain supply for stage 3A. VD = 28 V. | - | 1 |
| 11 | VD3_B | Drain supply for stage 3B. VD = 28 V. | - | 1 |
| 12 | RF-OUT | RF-Output pad. Matched to 50 ohm. | 150 x 200 | 4 |

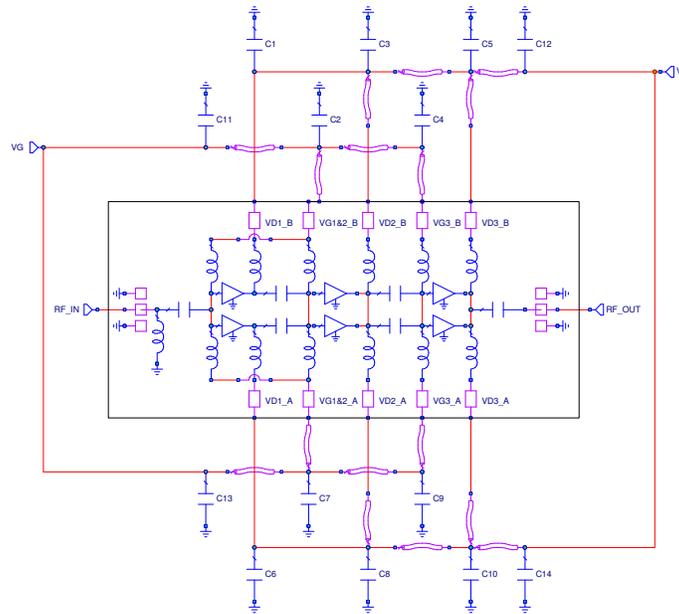
Notes:

- Attach bypass capacitor to pads 2-11 per application circuit.
- VG1&2_A and VG1&2_B are connected internally so it would be enough to connect either one for proper operation.
- VG3_A and VG3_B are connected internally so it would be enough to connect either one for proper operation.
- The RF Input and Output pad have a ground-signal-ground with a nominal pitch of 10 mil (250 um). The RF ground pads are 100 x 100 microns.

Die Assembly Notes:

- Recommended solder is AuSn (80/20) solder. Refer to Cree's website for the Eutectic Die Bond Procedure application note at <http://www.cree.com/~media/Files/Cree/RF/Application%20Notes/Appnote%202%20Eutectic.pdf>
- Vacuum collet is the preferred method of pick-up.
- The backside of the die is the Source (ground) contact.
- Die back side gold plating is 5 microns thick minimum.
- Thermosonic ball or wedge bonding are the preferred connection methods.
- Gold wire must be used for connections.
- Use the die label (XX-YY) for correct orientation.

Block Diagram Showing Additional Capacitors for Operation Over 6.0 to 12.0 GHz

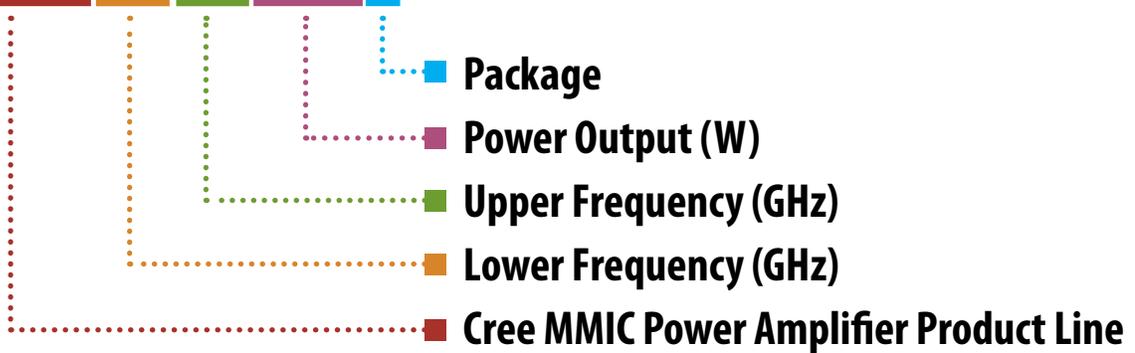


| Designator | Description | Quantity |
|--------------------------------|--|----------|
| C1,C2,C3,C4,C5,C6,C7,C8,C9,C10 | CAP, 51pF, +/-10%, SINGLE LAYER, 0.030", Er 3300, 100V, Ni/Au TERMINATION | 10 |
| C11,C12,C13,C14 | CAP, 680pF, +/-10%, SINGLE LAYER, 0.070", Er 3300, 100V, Ni/Au TERMINATION | 4 |

Notes:

- ¹ The input, output and decoupling capacitors should be attached as close as possible to the die- typical distance is 5 to 10 mils with a maximum of 15 mils.
- ² The MMIC die and capacitors should be connected with 1 mil gold bond wires.

CMPA601C025D



| Parameter | Value | Units |
|------------------------------|----------|-------|
| Lower Frequency | 6.0 | GHz |
| Upper Frequency ¹ | 12.0 | GHz |
| Power Output | 25 | W |
| Package | Bare Die | - |

Table 1.

Note¹: Alpha characters used in frequency code indicate a value greater than 9.9 GHz. See Table 2 for value.

| Character Code | Code Value |
|----------------|--------------------------------|
| A | 0 |
| B | 1 |
| C | 2 |
| D | 3 |
| E | 4 |
| F | 5 |
| G | 6 |
| H | 7 |
| J | 8 |
| K | 9 |
| Examples: | 1A = 10.0 GHz 2H = 27.0 GHz |

Table 2.



Product Ordering Information

| Order Number | Description | Unit of Measure |
|--------------|-----------------------------------|-----------------|
| CMPA601C025D | GaN MMIC Power Amplifier Bare Die | Each |



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